

Search Notes

Application/Control No.

10/542,171

Examiner

Karie O'Neill Apicella

Applicant(s)/Patent under
Reexamination

TANAKA ET AL.

Art Unit

1795

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Consulted with Dah-wei Yuan Re: claim language	3/10/2010	KOA
Searched in EAST	3/10/2010	KOA
Inventor search in eDAN	3/10/2010	KOA
Consulted with Pat Ryan Re: claim language	3/11/2010	KOA